

207.2 - Optical Microscope Linewidth Measurement (photomask)

SRM 2059 is a chrome-on-quartz photomask intended primarily for use in calibrating optical microscopes used to make dimensional measurements on antireflecting chromium integrated circuit photomasks, and supersedes SRM 473 Optical Microscope Linewidth Standard.

For further information see [SP 260-129](#), [SP 260-119](#), [SP 260-117](#) and [260-114](#)

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PLEASE NOTE: The tables are presented to facilitate comparisons among a family of materials to help customers select the best SRM for their needs. For specific values and uncertainties, the certificate is the only official source.

SRM	Description	Unit of Issue	Linewidth (µm)	Pitch (µm)
2059	Photomask Linewidth Calibration Standard	each	0.25 to 32.0	0.5 to 250